**Advanced characterization from the nanoscale to the single atom with a glance to the next in-situ performances**

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Scanning Transmission Electron microscopy is one of the most powerful characterization tool able to explore the 2D limits in semiconductors design.

Thanks to the sub-Å resolution combined with the incoherent contrast, the simple intuitive nature of the materials may be directly imaged and easily understood.

IMM-Headquarter owns one of the most powerful tool ever installed. Performance and results will be presented.